

10.1.8 Noise processes

Noise belongs to the stochastic signals – it is not possible to predict its exact course. The simplest quantitative description involves RMS-value, bandwidth, and spectral-envelope characteristic ($dP/df = \text{const.}$ or $1/f$). Supplementary specification regarding the time function is given by distribution (= probability-density-function) and cumulation (= probability-density-distribution), further information regarding the spectral distribution results from DFT- and $1/3^{\text{rd}}$ -octave-spectra. The literature listed at the end of this chapter may serve as guide to the theoretical principles for the description of random signals – the following listing in short introduces the most important noise processes.

a) Thermal noise (white noise i.e. $dP/df = \text{const.}$)

The temperature-dependent random-movements of free charge-carriers in a conductor (or in a resistor) lead to a thermal open-loop voltage at the connecting terminals (without any load); the RMS-value of this voltage is computed to:

$$\boxed{\tilde{U}_n = \sqrt{4kT \cdot \Delta f \cdot R}, \quad e_n = \sqrt{4kT \cdot R}} \quad 4kT = 1.70 \cdot 10^{-20} \text{ Ws}, \quad T = 308\text{K}$$

Open-loop noise-voltage density e_n and RMS-value of open-loop noise-voltage \tilde{U}_n for $\Delta f = 10 \text{ kHz}$ at resistor R :

$R =$	58.8	100	200	1k	10k	100k	1M	Ω
$e_n =$	1.00	1.30	1.8	4.1	13.0	41.2	130	nV/ $\sqrt{\text{Hz}}$
$\tilde{U}_n =$	0.1	0.13	0.18	0.41	1.3	4.12	13	μV

b) Shot noise (white, i.e. $dP/df = \text{const.}$)

Shot noise occurs in semiconductors and amplifier tubes. It is caused by statistic fluctuations of the current-flow through an interface layer between potentials. As an example, the electron-emission at an amplifier cathode may be modeled by a Poisson-distribution, with the current not continuously flowing but having statistic fluctuations. The real tube-noise is (given the space-charge conditions) slightly less than the theoretical maximum value calculated below for saturation [Meinke/Gundlach]:

$$\boxed{\tilde{I}_S = \sqrt{2e \cdot \Delta f \cdot I_0}, \quad i_S = \sqrt{2e \cdot I_0}, \quad \tilde{U}_S = \tilde{I}_S \cdot R} \quad 2e = 3.204 \cdot 10^{-19} \text{ As}$$

Noise-current density i_S , (RMS) noise-voltage \tilde{U}_S across a 10-k Ω -resistor for 10 kHz bandwidth, generated by DC I_0 :
 [f = Femto = 10^{-15} , p = Pico = 10^{-12}]

$I_0 =$	10 n	100 n	1 μ	10 μ	100 μ	1 m	10 m	A
$i_S =$	56,6 f	179 f	566 f	1,79 p	5,66 p	17,9 p	56,6 p	A/ $\sqrt{\text{Hz}}$
$\tilde{U}_S =$	56,6 n	179 n	566 n	1,79 μ	5,66 μ	17,9 μ	56,6 μ	V

The relation between shot-noise voltage \tilde{U}_S and thermal noise-voltage \tilde{U}_n depends on the DC voltage across the resistor and on the temperature voltage:

$$\boxed{\tilde{U}_S / \tilde{U}_n = \sqrt{U_0 / 2U_T}} \quad U_0 \text{ is the DC-voltage across resistor R; } 2U_T = 2 \cdot 26 \text{ mV} = 52 \text{ mV}.$$

c) Flicker noise (approximately pink, i.e. $dP/df \sim 1/f$)

This is low-frequency $1/f$ -noise caused by inhomogeneities in the material, deficiencies from manufacture, contaminations, and charge-fluctuations at surfaces. The designation stems from the burn spots jumping around (flickering) on the cathode of an amplifier tube. Simplified, the power-density decreases towards high frequencies with $1/f$ (pink noise). However, also observed were noise processes the spectral density of which does not correspond exactly to the $1/f$ -hyperbola. Flicker noise is only relevant in the low-frequency range.

The $1/f$ -noise caused in **resistors** carrying DC is characterized by the **Noise-Index NI** . Metal-film resistors (homogeneous crystal lattice structure) feature a small NI , while carbon composition resistors have large NI -values. In general, resistors with a high power-handling capacity (and requiring a larger volume) generate less noise than their low-power cousins of the same basic build.

$$NI = 20 \cdot \lg \frac{U_{10} / \mu V}{U_0 / V} \text{ dB}$$

$$U_{10} = U_0 \cdot 10^{-6} \cdot 10^{NI/20 \text{ dB}}$$

U_0 represents the DC-voltage across the resistor, U_{10} is the resulting $1/f$ -noise-voltage (RMS value) per frequency-decade; $NI = 0 \text{ dB} \Rightarrow 1 \mu\text{V/V}$.

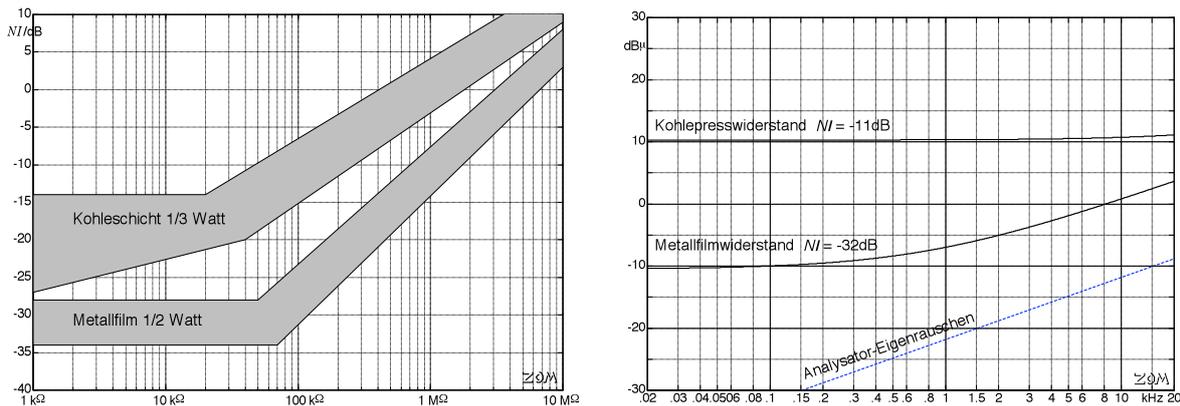


Abb. 10.1.30: left: noise-index NI for two different resistor types (Kohleschicht = carbon layer, Metallfilm = metal film). The grey areas show the scatter range between typical average values and typical maximum values. Right: measured $1/3^{\text{rd}}$ -octave noise-; dashed: intrinsic noise of analyzer. Pink noise results in frequency-independent $1/3^{\text{rd}}$ -octave-level voltage levels; for white noise the $1/3^{\text{rd}}$ -octave-levels rise with 10 dB/decade. Kohlepresswiderstand = carbon-composite resistor; Metallfilmwiderstand = metal film resistor; Analysator-Eigenrauschen = intrinsic noise of analyzer.

In **Fig. 10.1.30**, NI is listed for different resistor types. The areas marked in grey can only give very approximate orientation-values since the individual build has significant influence on the NI . In the right-hand section of the figure, we see measurements taken with two serially connected 68-k Ω -resistors carrying a DC of 1 mA. The two incoherent noise currents of the two resistors need to be added via a Pythagorean summation, and the mutual loading plus the loading via the analyzer (100 k Ω) has to be considered, as well. The metal-film resistors show a thermal white noise in the high-frequency region, and a current-dependent pink noise at low frequencies. In the carbon-composite resistors, current-dependent pink noise dominates throughout practically the whole frequency-range. These measurements give a noise index of the carbon-composite resistors of -11 dB, and a NI for metal film resistors of -32 dB. At low frequencies, the noise power densities of these two resistor-types therefore differ by a **factor of 126**. This factor is current-dependent; 1 mA is typical for plate-currents in preamplifiers.

Despite this considerable current-noise, carbon-composite resistors are listed as “**absolute high-end**” in the catalog of a retailer; one is very tempted to interpret this as “absolute upper range of the resistor noise”. The high-end fan must furthermore not be irritated by the fact the carbon-composite resistors have also considerably larger tolerances (compared to metal film resistors): maximum $\pm 10\%$ (carbon) vs. maximum $\pm 1\%$ (metal). Measurements confirm this: $+ 7\%$ (carbon) vs. $-0,3\%$ (metal). What about the price-difference? As expected, carbon-composite resistors are about 10 times as expensive as metal film resistors. Say no more: it’s about more noise – more tolerance to resistance – more money ...

What remains is the question whether differences in the current-noise play any role at all compared to the **shot-noise** generated in the tube. For an **ECC83** (12AX7), the equivalent input-noise voltage-density may be set to about $5 \text{ nV}/\sqrt{\text{Hz}}$ as a good approximation. With a voltage gain of 34 dB, this is equal to $250 \text{ nV}/\sqrt{\text{Hz}}$ at the plate, corresponding to a third-octave-level of 11.6 dB μ at 1 kHz (bandwidth 232 Hz). In comparison, the thermal noise from the **grid-resistors** ($68 \text{ k}\Omega // 68 \text{ k}\Omega = 34 \text{ k}\Omega$) typically found in the input-stages of guitar amps is five times as much (Chapter 10.1.7), reaching some ample **26 dB μ** in the third-octave band around 1 kHz. And how are we doing regarding the resistor-noise created by the plate-current? Given a 100-V-voltage-drop across the plate-resistor, and including a noise-index of $NI = -11 \text{ dB}$, we would be confronted with a 1-kHz-third-octave-level (open loop) of no more than 19 dB μ . With the loading by the internal impedance of the tube, this would decrease to about **11 dB μ** . Consequently, the current-noise of a carbon plate-resistor ($NI = -11 \text{ dB}$) at 1 kHz is lower than the noise of the preamplifier by 15 dB. For higher frequencies, this difference will grow even bigger, and only below 31 Hz, the current-noise would become dominant for the present model.

So: The current-noise of customary carbon resistors is inaudible in the investigated circuits

But: Supposedly there are carbon-composite resistors with NI not at -11 dB, but at 0 dB,
Or even higher – that could then just become audible.

Question: Is that worth 10 times the price? *Answer:* sure, the retailers are happy.

Two advantages are often highlighted to scientifically support the apparent superiority of the carbon-composite resistors: high power capacity with impulses, and small inductance. There may be scenarios in which the relative long thermal time-constant of the carbon-composites helps to avoid overheating, but pre-amp stages in guitar amps are not even remotely in the playing filed here. O.K. then: the reported low **inductance** of composite resistors will be crucial, won’t it? No, sorry, that aspect is utterly insignificant in the relevant frequency-range! The impedance of a 100-k Ω -resistor will increase by 0,000000002% at 100 kHz (with a inductance of 1 μH as a baseline). This increase should be seen relative to the manufacturing tolerances in carbon-composites: 10% according to data sheets. Plus: do not forget that 1 μH is already a high value; in data sheets we often find the entry “a few nano-henry”. BTW, our metal-o-phobic friends prefer not to mention capacitive reactive values, although these exist in carbon resistors, as well. Do you need to consider those? Course you do ... if you want to look beyond 1 MHz, where the reactive currents start to achieve some significance.

The never ending Internet saga of Carbon Comps: “Smooth, creamy sound...Are unstable, should not be used... Very clean and natural sound...Should be avoided...Taut and 3-dimensional sound...Make the working point drift away...Are the only choice for guitar amps...Never heard any difference in sound...Light-years ahead.” More examples are available ...

Literature: Motchenbacher/Connelly: Low-Noise Electronic System Design, Wiley 1993. Connor: Rauschen, Vieweg 1987. Hänslér: Statistische Signale, Springer 1991. Bendat/Piersol: Random Data, Wiley 1986.